Search Notes			
	<b>TEIR</b>		

Application/Control No.	Applicant(s)/Patent under Reexamination
10/030,497	REED, JOHN C.
Examiner	Art Unit
Hong Sang	1643

	SEARCHED			
Class	Subclass	Date	Examiner	
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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SEARCH NO (INCLUDING SEARC		)
	DATE	EXMR
EAST database search updated -enclosed	5/26/2006	H.S.
STN database search updated -enclosed	5/26/2006	H.S.
PubMed -enclosed	5/26/2006	H.S.